Special Issue

Materials Characterization Techniques

Message from the Guest Editor

To understand the structure of a substance, how to determine its properties, and how it works in technological applications, researchers use basic principles to address its scientific foundations as well as how it is processed and engineered. Material characterization techniques, with emphasis on practical applications and real-world case studies, provide the principles of widely used structure description, quality control, and process improvement. This special issue deals with the following scope:

- Scientific processes to characterize materials using modern technologies
- Analysis of materials' performance under specific use conditions
- Focuses on the interrelationships and interdependence between processing, structure, properties, and performance
- Covers electron, X-ray-photoelectron, and UV spectroscopy; scanning-electron, atomic-force, transmission-electron, laser-confocal-scanning-florescent microscopy, and X-ray diffraction

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Deadline for manuscript submissions

closed (10 November 2021)

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/si/82394

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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